

**Search Notes**

Application/Control No.

10/803,536

Examiner

Evan Dzierzynski

Applicant(s)/Patent under  
Reexamination

HAYASHI ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	466	6/12/2006	ED
	465	6/12/2006	ED
	460	6/12/2006	ED
	464	6/12/2006	ED

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST word search	6/12/2006	ED